## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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Patent Application Serial No	
Filing Date	September 5, 2003
Inventor	Jon P. Daley
Assignee	Micron Technology, Inc.
Group Art Unit	
Examiner	Pamela E. Perkins
Attorney's Docket No	MI22-2380
Customer No	021567
Title: Methods of Forming Patterned Photores	ist Layers Over Semiconductor
Substrates	

### SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References - See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. No copies of any cited U.S. patents or U.S. published applications are included herewith. Copies of all other cited art are attached. No admission is made regarding whether all the submitted references are prior art.

Citation of these references is respectfully requested.

A check in the amount of \$180.00 is enclosed to cover the fee specified under 37 C.F.R. § 1.17(p).

Respectfully submitted,

Dated: 3-16-06

Mark 8 Matkin Reg. No. 32,268

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Ratent Application Serial No.	10/655.997
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Title: Methods of Forming Patterned Photoresist Layers Over Semiconductor
Substrates

## SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References - See Attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

This Supplemental Information Disclosure Statement is being filed before the mailing of a first office action after the filing of a Request for Continued Examination. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. § 1.17(p) to Deposit Account No. 23-0925.

Respectfully submitted,

Dated: /2 - /-05

Mark S. Matkin Reg. No. 32,268

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ATTY. DOCKET NO. MI22-2380

SERIAL NO. 10/655,997

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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)

APPLICANT: Jon P. Daley

FILING DATE September 5, 2003

GROUP ART UNIT 2822

U.S. PATENT DOCUMENTS

*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing If Appr	Date opriate
-	AA	3,772,101	11/1973	Chumbres et al.				
	AB	5,677,102	10/1997	Shihara				
-	AC	6,096,634	08/2000	Nguyen				
	AD	6,165,834	12/2000	Agarwal et al.				
	AE	6,188,097	02/2001	Derderian et al.				
	AF	6,238,994	05/2001	Derderian et al.				
-	AG	6,255,035	07/2001	Minter et al.				
	AH	6,297,527	10/2001	Agarwal et al.				
	AI	6,376,149	04/2002	Grober et al.				<u> </u>
FOREIGN PATE	PATENT	Document	Date	Country	Class	Subclass	Translation	
		Number					Yes	No
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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APPLICANT: Jon P. Daley

**FILING DATE** 

**GROUP ART UNIT** 

#### September 5, 2003 2822 **U.S. PATENT DOCUMENTS** \*Examiner's Document Date Name Class Subclass Filing Date Initials Number If Appropriate AA 6,399,982 06/2002 Derderian et al. 01/2003 6,511,896 Basceri et al. AC 6,608,343 08/2003 Derderian et al. AD 09/2003 6,617,250 Basceri et al. ΑE 11/2003 6,649,466 Basceri et al. AF 6,744,093 06/2004 Agarwal et al. AG 6,746,916 06/2004 Agarwal et al. AH 6,777,739 08/2004 Agarwal et al. 6,780,766 08/2004 Basceri et al. FOREIGN PATENT DOCUMENTS Date Class Subclass Country Translation Number Yes No ΑK ΑL OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) АМ AN AO **EXAMINER** DATE CONSIDERED

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#### U.S. PATENT DOCUMENTS

*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing If Appro	Date priate
	<b>AA</b>	6,817,086	11/2004	Lu et al.				
	AB	6,900,497	05/2005	Agarwal et al.				
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